

PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the Application of

Hiroyuki NAGASAKA et al.

Application No.: 10/581,307

Filed: September, 26, 2006

Docket No.: 128253

For: EXPOSURE APPARATUS, EXPOSURE METHOD, METHOD FOR PRODUCING
DEVICE, AND OPTICAL PART

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

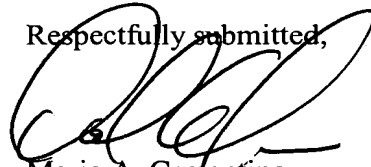
Sir:

Pursuant to 37 CFR §1.56, the attention of the Patent and Trademark Office is hereby directed to the references listed on the attached PTO-1449. Unless otherwise indicated herein, one copy of each reference is attached. It is respectfully requested that the information be expressly considered during the prosecution of this application, and that the references be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

- ☒ 1. This Information Disclosure Statement is being filed (a) within three months of the U.S. filing date of this non-CPA application, OR (b) before the mailing date of a first Office Action on the merits in the present application. No certification or fee is required.
- ☒ 2. In accordance with 37 CFR §1.98(a)(2)(ii), copies of any U.S. patents and patent application publications are not attached.
- ☒ 3. An English language Abstract of one or more non-English language reference is attached hereto. See References 118-130.

- ☒ 4. An English language translation of one or more Japanese Patent Publication cited herein has been obtained and is attached, but has not been reviewed for accuracy. See References 118-130.

Respectfully submitted,



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MAC:DAT/emt

Date: September 29, 2006

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Form PTO-1449 (REV. 1/06)		US Dept. of Commerce PATENT & TRADEMARK OFFICE		ATTY DOCKET NO. 128253		APPLICATION NO. 10/581,307	
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